between the test socket and the nest the electronic component can be pressed against, and lifted from, the test contacts of the test socket, characterised in that the at least one cleaning unit is designed in such a manner that during each test stroke the test contacts come into contact with the at least one cleaning unit, wherein the at least one cleaning unit is mounted in such a manner that it moves together with the nest, wherein the at least one cleaning unit is mounted to the nest or to a stamp that moves the nest.

Herein disclosed is a device for testing electronic components with at least one test socket with test contacts, with a nest in which at least one electronic component can be placed, and with at least one cleaning unit for the test contacts of the test socket,
wherein by means of a relative movement, which can be carried out as a test stroke, between the test socket and the nest the electronic component can be pressed against, and lifted from, the test contacts of the test socket,
wherein the at least one cleaning unit is designed in such a manner that during each test stroke the test contacts come into contact with the at least one cleaning unit, wherein the at least one cleaning unit is movably attached to the test socket.

According to the invention, the object is met by a device for testing electronic components, which device comprises the features of claim 1. Because the at least one cleaning unit is designed in such a manner that during each test stroke the test contacts come into contact with the at least one cleaning unit, the test contacts are cleaned before and/or after each test, and consequently

7. The device as set forth in any one of claims 3 to 6, characterised in that the at least one contact module is exchangeable.

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